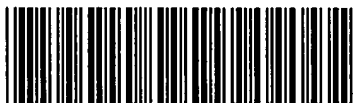


**Search Notes**

Application/Control No.

10/540,822

Examiner

John D. Lee

Applicant(s)/Patent under  
Reexamination

TAUSER ET AL.

Art Unit

2874

**SEARCHED**

Class	Subclass	Date	Examiner
359	326-332	9/21/2006	JDL
372	20-22	9/21/2006	JDL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO "WEST" Database searched. Key search terms: (picosecond or ps), (femtosecond or fs), (infrared or ir), pulse\$, stretch\$	9/21/2006	JDL